



## Product Change Notification / JAON-28QFPB827

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### Date:

19-Apr-2023

### Product Category:

Broadband Gateway

### PCN Type:

Manufacturing Change

### Notification Subject:

CCB 5014 Final Notice: Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at ASEM assembly site.

### Affected CPNs:

[JAON-28QFPB827\\_Affected\\_CPN\\_04192023.pdf](#)

[JAON-28QFPB827\\_Affected\\_CPN\\_04192023.csv](#)

### Notification Text:

**PCN Status:**Final Notification

**PCN Type:**Manufacturing Change

**Microchip Parts Affected:**Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

**Description of Change:**Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at ASEM assembly site.

### Pre and Post Change Summary:

		Pre Change				Post Change			
Fabrication Location	Die # 1	Global Foundries, Singapore - Fab 7 (GF07)				Global Foundries, Singapore - Fab 7 (GF07)			
	Die # 2	Global Foundries, Singapore - Fab 2 (GF02)		Microchip Technology Colorado – Fab 5 (MCSO)		Global Foundries, Singapore - Fab 2 (GF02)		Microchip Technology Colorado – Fab 5 (MCSO)	
Die Size	Die # 1	2.204 x 2.258 mm				1.932x1.860mm			
		Please see attached pre and post change comparison for Die # 1 Location							
	Die # 2	1.57 x 1.72 mm				1.57 x 1.72 mm			
Assembly Site		ASE Group -Malaysia (ASEM)				ASE Group -Malaysia (ASEM)			
Wire Material		CuPdAu				CuPdAu			
Die Attach Material		CRM1076DS				CRM1076DS			
Molding Compound Material		CEL-9240HF10AK-G1				CEL-9240HF10AK-G1			
Lead Frame Material		C194FH				C194FH			

**Impacts to Data Sheet:**None

**Change Impact**None

**Reason for Change:**To improve productivity by qualifying a new die size.

**Change Implementation Status:**In Progress

**Estimated First Ship Date:**May 20, 2023 (date code: 2320)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

**Time Table Summary:**

	May 2022				>	April 2023					May 2023				
Workweek	1 9	2 0	2 1	2 2		1 3	1 4	1 5	1 6	1 7	1 8	1 9	2 0	2 1	2 2
Initial PCN Issue Date				x											
Qual Report Availability									x						
Final PCN Issue Date									x						



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Affected Catalog Part Numbers (CPN)

LE9641PQC

LE9651PQC

LE9641PQCT

LE9651PQCT



**MICROCHIP**

**QUALIFICATION REPORT SUMMARY**  
RELIABILITY LABORATORY

**PCN#: JAON-28QFPB827**

**Date**  
**March 30, 2023**

**Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at ASEM assembly site.**



## MICROCHIP PACKAGE QUALIFICATION REPORT

<b>Purpose</b>	Qualification of a new die size (1.932x1.860mm) for Die #1 of selected Microsemi LE9641PQC, LE9651PQC, LE9641PQCT, and LE9651PQCT catalog part numbers (CPN) available in 48L VQFN (7x7x1.0mm) package assembled at ASEM assembly site.
<b>CCB No.</b>	5014
<b>CN</b>	E000123107
<b>QUAL ID</b>	R2200914 Rev A
<b>MP CODE</b>	3413J7M9CA01
<b>Part No.</b>	LE9641PQC
<b>Bonding No.</b>	BD-000310 Rev.04
<b><u>Package</u></b>	
<b>Type</b>	48LD VQFN
<b>Package size</b>	7 x 7 x 1 mm
<b><u>Lead Frame</u></b>	
<b>Paddle size</b>	232 x 232 mils
<b>Material</b>	C194
<b>Surface</b>	Selective AG Plating
<b>Process</b>	Etched
<b>Lead Lock</b>	No
<b>Part Number</b>	170048372135XL
<b>Material</b>	
<b>Epoxy</b>	CRM1076DS
<b>Wire</b>	CuPdAu
<b>Mold Compound</b>	CEL-9240HF10AK-G1
<b>Plating Composition</b>	Matte Tin



**MICROCHIP**

**PACKAGE QUALIFICATION REPORT**

**Manufacturing Information**

<b>Assembly Lot No.</b>	<b>Wafer Lot No.</b>	<b>Date Code</b>
ASEM231800031.000	GF07923119810.000	22314SA

**Result**

Pass  Fail

48LD VQFN (7x7x1 mm) assembled by ASEM pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<b>Precondition Prior Perform Reliability Tests (At MSL Level 3)</b>	<b>Electrical Test:</b> +25°C System: Chroma3650	JESD22-A113	154(0)	0/154		Good Devices
	Bake 150°C, 24 hrs. System: CHINEE 30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243	JIP/IPC/JEDEC J-STD-020E		0/154		
	<b>Electrical Test:</b> +25°C System: Chroma3650		154(0)	0/154	Pass	
<b>UNBIASED- HAST</b>	<b>Stress Condition:</b> +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		0/77		Parts had been pre-conditioned at 260°C  77 units
	<b>Electrical Test:</b> +25°C System: Chroma3650		77(0)	0/77	Pass	
	<b>Stress Condition:</b> +130°C/85%RH, 192 hrs. System: HAST 6000X			0/77		
	<b>Electrical Test:</b> +25°C System: Chroma3650		77(0)	0/77	Pass	
<b>Wire sweep</b>	Wire sweep Inspection 20 Wires	-	20(0) Wires	0/20	Pass	